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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/574,145	03/29/2006	Leendert Van Der Tempel	GB 030180	3766
	7 7590 04/15/2008 ILIPS INTELLECTUAL PROPERTY & STANDARDS		EXAMINER	
P.O. BOX 3001			PEACE, RHONDA S	
BKIAKCLIFF	MANOR, NY 10510		ART UNIT PAPER NUMBER	
		2874		
			MAIL DATE	DELIVERY MODE
			04/15/2008	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)				
Office Action Commons	10/574,145	VAN DER TEMPE	L, LEENDERT			
Office Action Summary	Examiner	Art Unit				
	Rhonda S. Peace	2874				
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence ad	ldress			
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 16(a). In no event, however, may a reply be tim ill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONEI	J. nely filed the mailing date of this c D (35 U.S.C. § 133).	,			
Status						
1) Responsive to communication(s) filed on						
	- action is non-final.					
3) Since this application is in condition for allowan	ice except for formal matters, pro	secution as to the	e merits is			
closed in accordance with the practice under E	x <i>parte Quayle</i> , 1935 C.D. 11, 45	53 O.G. 213.				
Disposition of Claims						
4)⊠ Claim(s) <u>1-20</u> is/are pending in the application.						
4a) Of the above claim(s) is/are withdraw	vn from consideration					
5) Claim(s) is/are allowed.	m nem censideration.					
6)⊠ Claim(s) <u>1-3,5-11 and 13-20</u> is/are rejected.	· · · · · · · · · · · · · · · · · · ·					
7) Claim(s) is/are objected to.						
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Application Papers						
9)☐ The specification is objected to by the Examiner.						
10)⊠ The drawing(s) filed on <u>29 <i>March 2006</i></u> is/are: a)⊠ accepted or b)⊡ objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).						
11)☐ The oath or declaration is objected to by the Ex	aminer. Note the attached Office	Action or form P7	ΓO-152.			
Priority under 35 U.S.C. § 119						
12)⊠ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)⊠ All b)□ Some * c)□ None of:						
 Certified copies of the priority documents 	s have been received.					
Certified copies of the priority documents	have been received in Application	on No				
3. Copies of the certified copies of the prior	ity documents have been receive	ed in this National	Stage			
application from the International Bureau	application from the International Bureau (PCT Rule 17.2(a)).					
* See the attached detailed Office action for a list of the certified copies not received.						
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview Summary	(PTO-413)				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/Mail Da	nte				
3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 5) Notice of Informal Patent Application 6) Other:						
. 200	-/					

DETAILED ACTION

Priority

Receipt is acknowledged of papers in this National Stage application from the International Bureau (PCT Rule 17.2(a)), submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 1-3, 6-11, 13, and 15-20 are rejected under 35 U.S.C. 102(e) as being anticipated by Hioki et al (US 6,987,284).

Pertaining to claims 1 and 18, Hioki et al discloses a method of fabricating a device as seen in Figure1B comprising first layers 102 and 104, and a second layer 103, wherein the first layers 102 and 104 are flexible, and the second layer 103 has a corrugated structure and is in contact with the first layers 102 and 104 along a substantial portion of said second layer 103 so as to prevent fracture of the second layer 103 when the first layers 102 and 104 are deformed. The second layer 103 comprises a plurality of crest and trough portions, wherein the length of each crest and

trough portion is selected to prevent fracture when the first layers **102** and **104** are deformed to a predetermined radius of curvature. See Figures 1B and 14-18, col. 7 lines 35-49, col. 9 lines 28-39, col. 11 lines 8-39.

Concerning claims 19 and 20, Hioki et al further discloses forming cracks **301** in the second layer **103** by subjecting said layer **103** to a predetermined radius of curvature. Said cracks **301** are then chemically polished to form the crests and troughs of layer **103**, thereby teaching the length of the said crests and troughs are determined based upon the spacing of said cracks **301**. See Figures 11-12, 10 lines 18-47. Moreover, as shown in Figure 18, the length of the troughs and crests may also be determined based upon the average spacing between the cracks **301**, such that cracks **301** spaced according to the average spacing between cracks **301** occur along the peak of the said troughs of second layer **103**. See Figure 18, col. 11 lines 28-39.

Addressing claims 2 and 3, Hioki et al discloses the first layer **104** is a substrate, as layer **104** comprises a block layer of material on which circuitry is formed. See Figure 1B, and col. 7 lines 38-41. Additionally, Hioki et al discloses a third layer **101** in contact with said first layer **102**, wherein the third layer **101** comprises a substrate, and the first layer **102** comprises a coating on said substrate. See Figure 1B and col. 7 lines 35-38.

With regard to claims 6-8, Hioki et al discloses the second layer **103** as a coating of the first layer **102**, as the second layer **103** completely covers the first layer **102**. See col. 7 lines 35-38. Moreover, the first layer **102** exhibits a corrugated topography, as seen in Figure 1B. The second layer **103** comprises a series of adjoining troughs and

crests, wherein each trough and ridge exhibits substantially flat portions, as seen in Figures 1B, 9, and 10, for example. See col. 13 lines 16-36.

Pertaining to claims 9-11 and 13, Hioki et al discloses the second layer 103 has a waveform-type corrugated structure and is in contact with the first layers 102 and 104 along a substantial portion of said second layer 103 so as to prevent fracture of the second layer 103 when the first layers 102 and 104 are deformed. See col. 11 lines 8-15. Moreover, as shown in Figure 18, the length of the troughs and crests may also be determined based upon the average spacing between the cracks 301, such that cracks 301 spaced according to the average spacing between cracks 301 occur along the peak of the said troughs of second layer 103, wherein the length of each flat portion, as seen in Figure 18, is less than the average spacing between cracks 301. See Figure 18, col. 11 lines 28-39.

Concerning claims 15-17, Hioki et al discloses the second layer **103** is formed of a thin glass (silicon dioxide) plate which is a transparent light-conducting oxide material. See col. 7 lines 35-37. Moreover, Hioki et al discloses using the above-described device in a display apparatus. See col. 1 lines 15-17.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

The factual inquiries set forth in *Graham* **v.** *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

- 1. Determining the scope and contents of the prior art.
- 2. Ascertaining the differences between the prior art and the claims at issue.
- 3. Resolving the level of ordinary skill in the pertinent art.
- 4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

Claim 5 is rejected under 35 U.S.C. 103(a) as being unpatentable over Hioki et al (US 6,987,284), in further view of Nanoux (US 3,936,341).

Pertaining to claim 5, Hioki et al discloses the display device as described above. Hioki et al discloses the third layer 101 may be formed of a thermoplastic polyimide resin. See col. 11 lines 40-50. However, Hioki et al does not disclose the use of acrylate lacquer for the adhesion layer 102. Nanoux discloses the use of an adhesive acrylate lacquer provided on a thermoplastic resin. See col. 1 lines 60-64, and the abstract. It would have been obvious to one of ordinary skill in the art to form the first layer of Hioki et al with a acrylate lacquer, as Nanoux et al discloses such a material provides excellent adhesion properties with a thermoplastic resin and has good resistance to delamination. See Nanoux, col. 1 lines 54-64. Moreover, it has been held to be within the general skill of a worker in the art to select a known material on the basis of its suitability for the intended use as a matter of obvious design preference. *In re Leshin*, 125 USPQ 416.

Claim 14 is rejected under 35 U.S.C. 103(a) as being unpatentable over Hioki et al (US 6,987,284), in further view of Takami et al (US 6,697,131).

Page 6

Addressing claim 14, Hioki et al discloses the display device as described above, including that the substrate 104 may be formed of silicon oxide or silicon nitride. See col. 7 lines 64-66. However, Hioki et al does not disclose the substrate **104** as being formed of the thermoplastic resin polyvinyl chloride. Takami et al discloses a liquid crystal display having substrate 1, 1', 2, and 2' upon which a plurality of electrodes 5a, 5a', 5b, and 5b' are formed. Moreover, Takami et al discloses said substrates may be formed of inorganic glass or organic compounds such as polyvinyl chloride. See Takami et al, col. 13 lines 65-67 and col. 14 lines 1-9. It would have been obvious to one of ordinary skill in the art to use polyvinyl chloride as a material for substrate 104, as polyvinyl chloride is transparent, and provides electrical isolation to electrodes formed thereon, thereby eliminating the need for an additional insulator between substrate 104 and the electrodes 112 in the device of Hioki et al. Furthermore, it has been held to be within the general skill of a worker in the art to select a known material on the basis of its suitability for the intended use as a matter of obvious design preference. In re Leshin, 125 USPQ 416.

Allowable Subject Matter

Claims 4 and 12 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and *any intervening claims*.

The following is a statement of reasons for the indication of allowable subject matter: The applicable prior art does not disclose or reasonably suggest the device as described in either claims 4 or 12. The most applicable prior art, Hioki et al, discussed

Application/Control Number: 10/574,145 Page 7

Art Unit: 2874

above, does not disclose or reasonably suggest the substrate 101 having a corrugated topography, and also does not disclose or reasonably suggest the substantially flat portions of said crest and troughs being interconnected to provide a continuous path for an electric current.

Conclusion

The following art made of record and not relied upon is considered pertinent to applicant's disclosure: Bharawaj et al (US 2005/0244614), Tseng et al (US 2007/0001202), and Satoh (US 2008/0055831).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Rhonda S. Peace whose telephone number is (571)272-8580. The examiner can normally be reached on M-F (8-5).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Rodney Bovernick can be reached on (571) 272- 2344. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/574,145 Page 8

Art Unit: 2874

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Rhonda S. Peace/ Examiner, Art Unit 2874

> /Michelle R. Connelly-Cushwa/ Primary Examiner, Art Unit 2874